

**Search Notes****Application/Control No.**

10/775,080

**Examiner**

Chun-Kuan (Mike) Lee

**Applicant(s)/Patent under Reexamination**

SAKIYAMA ET AL.

**Art Unit**

2181

**SEARCHED**

Class	Subclass	Date	Examiner
710	8	4/22/2007	CHUN-KUAN Lee
710	13	4/22/2007	
710	17	4/22/2007	
710	68	4/22/2007	
710	74	4/22/2007	
710	300-301	4/22/2007	V

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(EAST) US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB Inventor search utilising eDan and EAST	4/22/2007	CHUN-KUAN Lee

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner